
Nanotehnologije - Smernice za pripravo vzorcev, odkrivanje, identifikacijo in karakterizacijo nanoobjektov v anorganskih dodatkih, vključenih v živilske matrice, s spICP-MS in EM-EDX

Nanotechnologies - Guidelines for sample preparation, detection, identification and characterization by spICP-MS and EM-EDX of nano-objects in inorganic additives incorporated in food matrices

Nanotechnologien - Richtlinien zur Charakterisierung von nanoobjekthaltigen Zusatzstoffen in Lebensmitteln

Nanotechnologies - Directives pour la caractérisation d'additifs contenant des nanoobjets dans des denrées alimentaires

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detection, identification and characterization by spICP-MS
and EM-EDX of nano-objects in inorganic additives
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von nanoobjekthaltigen Zusatzstoffen in Lebensmitteln

This draft Technical Specification is submitted to CEN members for Vote. It has been drawn up by the Technical Committee CEN/TC 352.

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Recipients of this draft are invited to submit, with their comments, notification of any relevant patent rights of which they are aware and to provide supporting documentation.

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Contents

Page

European foreword	5
Introduction	6
1 Scope.....	8
2 Normative references.....	8
3 Terms and definitions	8
4 General considerations.....	10
5 Overview of the applicability and limitations of EM and spICP-MS.....	12
5.1 General.....	12
5.2 EM-EDX	12
5.2.1 General.....	12
5.2.2 Scanning electron microscope (SEM)	13
5.2.3 Transmission electron microscopy (TEM)	13
5.2.4 Energy Dispersive X-ray Spectroscopy (EDX).....	14
5.2.5 Image acquisition and calibration	14
5.2.6 Image analysis.....	14
5.2.7 Data analysis and reporting.....	15
5.2.8 Measurement uncertainties.....	15
5.3 spICP-MS.....	16
5.3.1 General considerations.....	16
5.3.2 Considerations for specific food additives	17
5.3.3 Data analysis and reporting.....	18
5.3.4 Measurement uncertainties.....	18
5.4 Method selection	18
6 Guidance on sample preparation.....	20
6.1 General.....	20
6.2 Extraction or digestion protocols for different types of food matrices.....	20
6.3 Removal of matrix components and residues	21
6.3.1 General.....	21
6.3.2 Removal of matrix components and residues for spICP-MS analysis	21
6.3.3 Removal of matrix components and residues for EM analysis.....	21
6.4 Dispersion stabilisation	21
6.5 Specific considerations for EM-EDX measurements	22
6.5.1 Particle concentration	22
6.5.2 Deposition of the particles on the grids or on the substrate.....	22
6.6 Specific consideration for spICP-MS measurements.....	22
6.6.1 Specific sample preparation steps.....	22
6.6.2 Detector saturation	23
6.6.3 Data processing and data reporting.....	23
7 Examples of specific protocols for the extraction and the analysis of E 171 and E 172 in different food matrices	24
Annex A (informative) Context of food additives and nano-objects.....	25
A.1 General.....	25
A.2 Titanium dioxide (E 171).....	25

A.3	Iron oxides and hydroxides (E 172)	26
A.4	Synthetic Amorphous Silica (E 551)	26
Annex B (informative) Protocol for the analysis of E 171 in sugar shell confectionary products by spICP-MS.....		27
B.1	Introduction	27
B.2	Apparatus and Equipment.....	27
B.3	Chemicals and reagents.....	28
B.4	Analysis	28
B.5	Case study: E 171 in Sugar Shell Confectionary by spICP-MS.....	33
Annex C (informative) Protocols for the analysis of E 171 in complex food matrices by EM-EDX.....		36
C.1	Introduction	36
C.2	Food samples.....	36
C.3	Apparatus, equipment and consumables.....	37
C.4	Chemicals and reagents.....	37
C.5	Preparation of the stock solutions	37
C.6	Calculations and preliminary information.....	38
C.7	Procedure	38
C.8	Results	40
Annex D (informative) Protocol for the analysis of E 172 in sugar shell confectionary products by EM-EDX		44
D.1	Introduction	44
D.2	Equipment.....	44
D.3	Chemicals and reagents.....	44
D.4	Analysis of the additive incorporated in sugar shell confectionary.....	44
D.5	Optional: Analysis of the pristine additive	47
D.6	Case study: E 172 included in sugar-based cake decorations	48
Annex E (informative) Protocol for the analysis of E 172 in sugar shell confectionary products by spICP-MS.....		51
E.1	Introduction	51
E.2	Apparatus and equipment.....	51
E.3	Chemicals and reagents.....	52
E.4	Sample preparation	52
E.5	Case study: E 172 (ii) and E 172 (iii) in Sugar-based Confectionary by spICP-MS	56
Annex F (informative) Preliminary measurement of unknown samples.....		61
F.1	General	61
F.2	Chemical and physical properties of the additive of interest.....	61
F.3	Total mass of the additive in the matrix.....	61

FprCEN/TS 18267:2025 (E)

F.4	Stability of the pristine additive in liquid-based media	61
	Annex G (informative) Best practice for the sonication of the particles.....	62
G.1	Determination of the acoustic power delivered by the sonication device.....	62
G.2	Precautions to be taken if you use the direct tip sonication approach	64
	Annex H (informative) Calculation of the centrifugation speed	66
	Annex I (informative) Example of particle deposition protocols for EM measurements	67
I.1	Static deposition of negatively charged nanoparticles on a positively charged grid.....	67
I.2	Deposition of negatively charged nanoparticles on a positively charged silicium substrate by spin-coating.....	67
	Bibliography	68

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European foreword

This document (FprCEN/TS 18267:2025) has been prepared by Technical Committee CEN/TC 352 “Nanotechnologies”, the secretariat of which is held by AFNOR.

This document is currently submitted to the Vote on TS.

This document has been prepared under a standardization request addressed to CEN by the European Commission. The Standing Committee of the EFTA States subsequently approves these requests for its Member States.

The purpose of this document is to assist in the use of the following standards in the context of extraction, detection identification and quantification of nano-objects-in pure additives and in additives contained in food matrices:

- EN ISO 3696:1995, *Water for analytical laboratory use — Specification and test methods (ISO 3696:1987)*
- CEN/TS 17273:2018, *Nanotechnologies — Guidance on detection and identification of nano-objects in complex matrices*
- CEN ISO/TS 19590:2024, *Nanotechnologies — Characterization of nano-objects using single particle inductively coupled plasma mass spectrometry (ISO/TS 19590:2024)*
- EN ISO 19749:2023, *Nanotechnologies — Measurements of particle size and shape distributions by scanning electron microscopy (ISO 19749:2021)*
- EN ISO 21363:2022, *Nanotechnologies — Measurements of particle size and shape distributions by transmission electron microscopy (ISO 21363:2020)*
- CEN ISO/TS 23302:2022, *Nanotechnologies — Requirements and recommendations for the identification of measurands that characterise nano-objects and materials that contain them (ISO/TS 23302:2021)*